

Connecting and Integration of the Instrumentation in the DCM

Y. Leclercq, F. Crisci for WP3



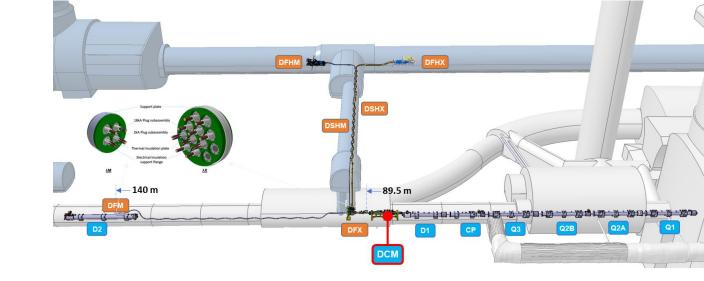
HL-LHC Magnet Circuit Instrumentation Day 2023

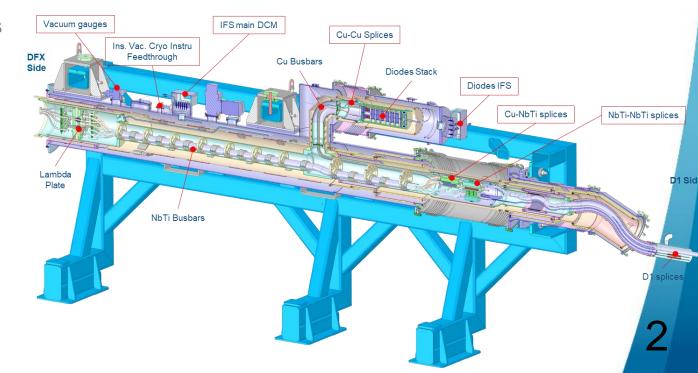
DCM overview

- DCM part of IT chain of magnets cryostats
 - Common cryogenic volume
 - Common insulation vacuum volume
 - Electrical continuity of conductors
- Functions
 - Integrate and provide operating conditions for:
 - Cold diodes
 - Lambda plates
 - Route SC busbars
 - Present instrumentation feedthroughs and interfaces
 - Interface with WP6a
- Key features wrt instrumentation
 - Two IFS flanges
 - Cold diodes
 - Main DCM)
 - Two groups of splices
 - Diodes interconnect (x5)
 - DCM-D1 interconnect (x24)









Instrumentation scheme for the DCM

Electrical V-taps : <u>LHCLSDIX0001</u>

DCM main IFS: 31 V-taps

Diodes IFS: 14 V-taps + 7 I-taps

Cryogenic: <u>LHCLSQRG0041</u>

DCM main IFS

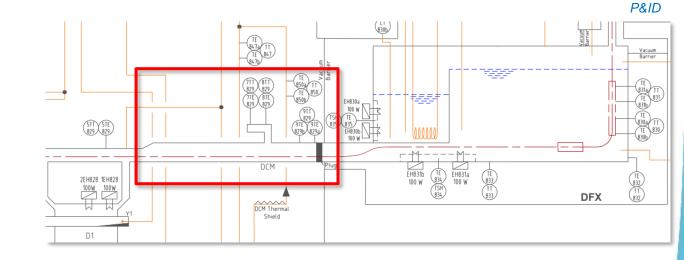
0 TT for Tunnel version

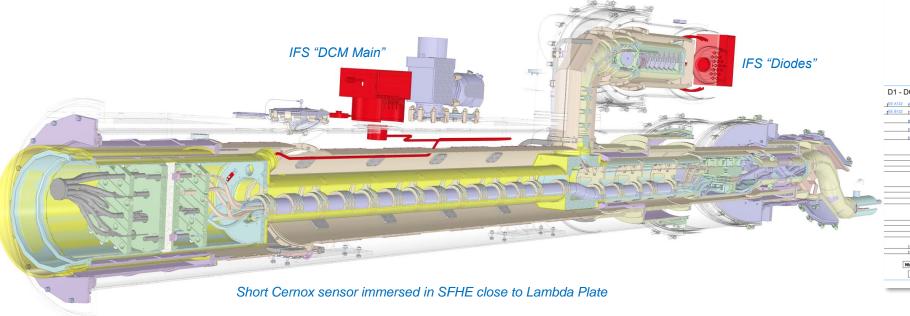
• 2 TT for String version

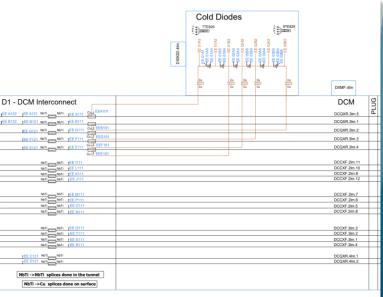
Diodes IFS: 4 TT

Insulation vacuum : 2 TT

No vacuum gauges installed on DCM







Wires connection, routing and testing

Wires types : same wires as for magnets & WP6a

	Туре	AWG	Conductor	Layout	Insulation	OD
TT in helium	Axon - HT3007	AWG30	Copper	4-in-1	Polyimide	1.70 mm
TT in vacuum	Habia - B/Mang 0.12 N4		Manganin	4-in-1	Polyamide	1.00 mm
V-taps	Axon - HH2619	AWG26	Copper	Single	Polyimide	0.95 mm
I-taps	Axon – HH2019	AWG20	Copper	Single	Polyimide	1.50 mm

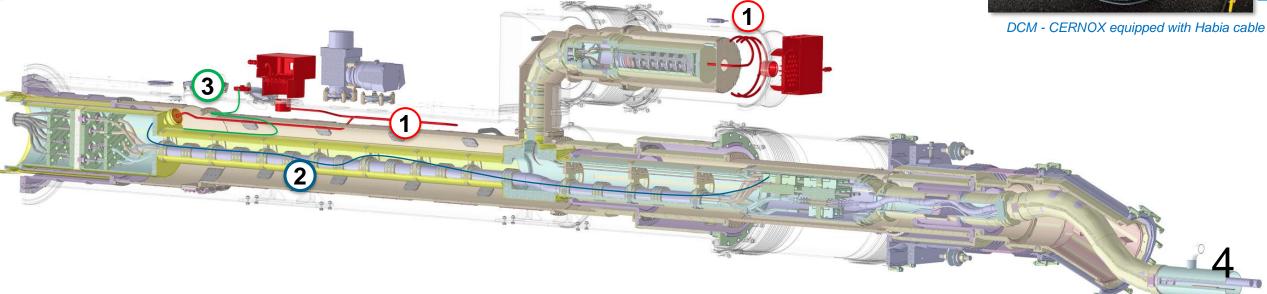


DCM IFS capillaries in production in SMI2

• Routing:

- 1. From IFS flange to Helium vessel:
 - Wires bundle in fibre glass sleeves
 - Capillaries pre-assembled, cold shocked and QC tested before installation
- 2. Inside helium vessel : fibre glass sleeves along busbars
- 3. Insulation vacuum: usual routing technique with cryogenic tape





Wires connection, routing and testing

Wires connection

- TT-sensors
 - Inside He vessel: connected at installation
 - Insulation vacuum: pre-wired, connection to MIL8
- V-taps
 - Installed during soldering operation
 - Follow same procedures as for magnets EDMS 236866

Testing:

- EDMS 2747011 in work with MCF
- HV tests at RT in air from 10 kV down to 1.5 kV
- Electrical Design Criteria document not released yet

CERN





2366866 5.0 **VALID** LHC-MQXFB-FP-0026

Date: 2023-03-15

FABRICATION PROCEDURE HL-LHC / WP03

Aimant MQXFB Nb₃Sn **Connexions Internes de l'aimant MQXFB** Etape K.13 du MIP [2]

							HV test sequence	
Test ID	Component	Test configuration under RT, air, 1 bara	DC Test Voltage	Voltage Ramp Rate (V/s)	Leakage Current Requirement (μΑ)	Testing time at DC test voltage (s)	Illustration	
Phase 0:	individual component		T		T	,		
0	IFS wiring for DCM IFS: V-taps, Cryo heaters and TT_sensors, before connection to anything, as a bunch of wires	V-Taps & EH wires, wire to other wires shorted and connected to GND, included TT sensors wires	10 kV	200	<10	60		
		TT conductors: 4 wires shorted (impossible to test wire to wire since the TT sensor is connected to the 4 wires) vs all others wires shorted and connected to GND, included TT sensors wires	200 V	10	<0.5			
B2 connection	IFS wiring for DCM IFS before	V-Taps & EH wires, wire to other wires shorted and connected to GND, included TT sensors wires, with the IFS tube grounded	10 kV	200	<10	60		
	in IFS tube, before shaping	TT conductors: 4 wires shorted (impossible to test wire to wire since the TT sensor is connected to the 4 wires) vs all others wires shorted and connected to GND, included TT sensors wires, with the IFS tube grounded	200 V	10	<0.5			
	IFS wiring for DCM IFS before	V-Taps & EH wires, wire to other wires shorted and connected to GND, included TT sensors wires, with the IFS tube grounded	10 kV	200	<10			
A2	connection to anything, after inserting in IFS tube, after shaping, after thermal shock at LN2	TT conductors: 4 wires shorted (impossible to test wire to wire since the TT sensor is connected to the 4 wires) vs all others wires shorted and connected to GND, included TT sensors wires, with the IFS tube grounded	200 V	10	<0.5	60		
	Diadas shada wikh ah and lasada wisa	V-Taps & I-taps shorted together vs (GND + TT sensors wires)	3 kV	200	<10	60	Territo.	
A1 Diodes sta	Diodes stack, with short length wires	TT conductors: 4 wires shorted vs all others wires shorted and connected to GND, including other TT sensors wires	100 V	10	<0.5			
Phase 1:	Intermediate testing during DCM Main F	lorizontal assembly	!	1				
	Plugs assembled on the Lambda Plate	bus bars vs GND and in between for 4-in-1 type						
B1		plugs, with DCM cryostat grounded No TT sensors nor wires at this stage	3 kV ???	200	<10	60	- Constant of the Constant of	
ca B4 instr	Main DCM fully equipped with the capillary tube mounted and the	bus bars and EH wires vs GND + TT sensors wires, with DCM cryostat grounded	3 kV	200	<10	60	Car of the	
	instrumentation wires connected at the cold part and at the warm part (to the DCM cover flange)	TT conductors: 4 wires shorted vs all others wires shorted and connected to GND, including other TT sensors wires, with DCM cryostat grounded	100 V	10	<0.5			
	Main DCM fully equipped with the capillary tube mounted and the insrumentation wires connected at the cold part and at the warm part (to the DCM cover flange)	bus bars and EH wires vs GND + TT sensors wires, with DCM cryostat grounded	2 kV	200	<10			
		TT conductors: 4 wires shorted vs all others wires shorted and connected to GND, including other TT sensors wires, with DCM cryostat grounded	100 V	10	<0.5	60		
Phase 2:	Intermediate testing during Diodes cryo	stat assembly						
A4 as:	Diode cryostat with diodes stack assembled in it and wires routed up to IFS flange	V-Taps & I-taps shorted together vs (GND + TT sensors wires)	2 kV	200	<10	60		
		TT conductors: 4 wires shorted vs all others wires shorted and connected to GND, including other TT sensors wires	100 V	10	<0.5			
A5 asse	Diode cryostat with diodes stack assembled in cryostat, wires routed up to IFS flange with IFS box installed	V-Taps & I-taps shorted together vs (GND + TT sensors wires)	2 kV	200	<10	60		
		TT conductors: 4 wires shorted vs all others wires shorted and connected to GND, including other TT sensors wires	100 V	10	<0.5			
Finale QC	on Main DCM assembly before dispatch							
		bus bars (diodes V-Taps & I-taps shorted						
C1 equipped with the diodes stack	Main DCM in final configuration: fully	together) and EH wires vs (GND + TT sensors wires)	1500 V	200	<10	60		
	installed and all instrumentations	TT conductors: 4 wires shorted vs all others wires shorted and connected to GND, including	100 V	10	<0.5			



Documentation

- V-taps layout LHCLSDIX0001
- Cryogenic instrumentation : <u>LHCLSQRG0041</u>
- Electrical design criteria EDMS 2747011
- IFS flanges : EDMS 2896437 & 2896449



